

<b>Notice of References Cited</b>	Application/Control No. 10/022,851		Applicant(s)/Patent Under Reexamination THIBEAULT ET AL.	
	Examiner Qutbuddin Ghulamali		Art Unit 2611	Page 1 of 1

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#### NON-PATENT DOCUMENTS

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	U	Hamamoto et al, IEEE, Journal of Solid State, vol. 33, No. 5 May 1998, pages 770-778.			
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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